### **Description**

The AOD538 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.



### TO-252-2L

### **General Features**

 $V_{DS} = 30V I_{D} = 150A$ 

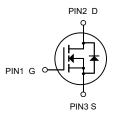
 $R_{DS(ON)}$  < 2.9 m $\Omega$ @  $V_{GS}$ =10V

### **Application**

Battery protection

Load switch

Uninterruptible power supply



N-Channel MOSFET

### **Package Marking and Ordering Information**

Product ID	Pack	Brand	Qty(PCS)
AOD538	TO-252-2L	HXY MOSFET	2500

### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	30	V
Vgs	Gate-Source Voltage	±20	V
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	150	А
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	80	А
IDM	Pulsed Drain Current <sup>2</sup>	450	А
EAS	Single Pulse Avalanche Energy <sup>3</sup>	580	mJ
las	Avalanche Current	60	А
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	87	W
Тѕтс	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
RθJA	Thermal Resistance Junction-Ambient 1	62	°C/W
RθJC	Thermal Resistance Junction-Case1	2.1	°C/W



# Electrical characteristic ( $T_J = 25^{\circ}C$ unless otherwise specified )

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain to source breakdown voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	30			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown voltage temperature coefficient	I <sub>D</sub> =250uA, referenced to 25°C		0.02		V/°C
ı D	Drain to source leakage current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V			1	uA
I <sub>DSS</sub>	Drain to source leakage current	V <sub>DS</sub> =24V, T <sub>J</sub> =125°C			50	uA
	Gate to source leakage current, forward	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V			100	nA
I <sub>GSS</sub>	Gate to source leakage current, reverse V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V				-100	nA
$V_{\rm GS(TH)}$	Gate threshold voltage	$V_{DS}=V_{GS}$ , $I_{D}=250uA$	1.2		2.4	V
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =30A,T <sub>J</sub> =25°C		2.2	4.8	mΩ
$R_{DS(ON)}$	Drain to source on state resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =30A,T <sub>J</sub> =25°C		1.5	2.9	mΩ
		V <sub>GS</sub> =10V, I <sub>D</sub> =30A,T <sub>J</sub> =125°C		2.5		mΩ
$G_fs$	Forward transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =30A		73		S
C <sub>iss</sub>	Input capacitance			6272		pF
$C_{oss}$	Output capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, f=1MHz		1022		
C <sub>rss</sub>	Reverse transfer capacitance			718		
$t_{d(on)}$	Turn on delay time			20		ns
t <sub>r</sub>	Rising time	$V_{DS}$ =15V, $I_{D}$ =30A, $R_{G}$ =4.7 $\Omega$ ,		58		
t <sub>d(off)</sub>	Turn off delay time	V <sub>GS</sub> =10V (note 4,5)		158		
t <sub>f</sub>	Fall time	(11010-1,0)		77		
$Q_g$	Total gate charge	V <sub>DS</sub> =24V, V <sub>GS</sub> =10V, I <sub>D</sub> =30A,		143		nC
$Q_gs$	Gate-source charge	I <sub>G</sub> =5mA		17		
$Q_{gd}$	Gate-drain charge	(note 4,5)		43		
$R_g$	Gate resistance	V <sub>DS</sub> =0V, Scan F mode		4.2		Ω
I <sub>s</sub>	Continuous source current	Integral reverse p-n Junction			110	A
I <sub>SM</sub>	Pulsed source current	diode in the MOSFET			440	Α
V <sub>SD</sub>	Diode forward voltage drop.	I <sub>S</sub> =45A, V <sub>GS</sub> =0V			1.4	V
t <sub>rr</sub>	Reverse recovery time	I <sub>S</sub> =30A, V <sub>GS</sub> =0V,		26		ns
Q <sub>rr</sub>	Reverse recovery charge dI <sub>F</sub> /dt=100A/us			10		nC

### ※. Notes

- Repeatitive rating : pulse width limited by junction temperature. L =0.5mH,  $I_{AS}$  =48A,  $V_{DD}$ =30V,  $R_{G}$ =25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}$ C  $I_{SD}$  ≤30A, di/dt = 100A/us,  $V_{DD}$  ≤ BV $_{DSS}$ , Staring  $T_{J}$  =25 $^{\circ}$ C Pulse Test : Pulse Width ≤ 300us, duty cycle ≤ 2%. 1.
- 3.

### **Typical Electrical and Thermal Characteristics**

Fig. 1. On-state characteristics

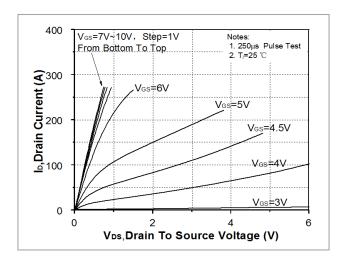


Fig. 3. On-resistance variation vs. drain current and gate voltage

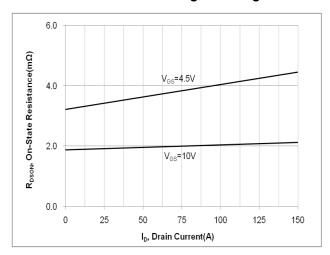


Fig 5. Breakdown voltage variation vs. junction temperature

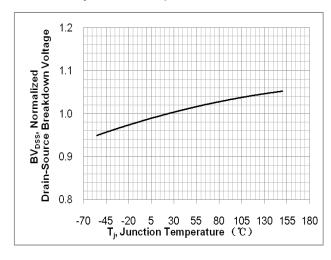


Fig. 2. Transfer Characteristics

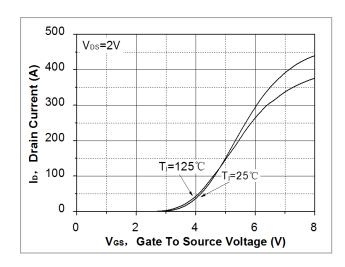


Fig. 4. On-state current vs. diode forward voltage

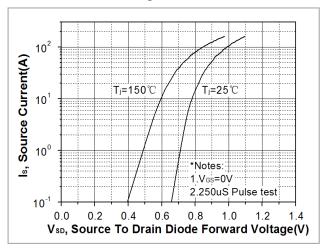


Fig. 6. On-resistance variation vs. junction temperature

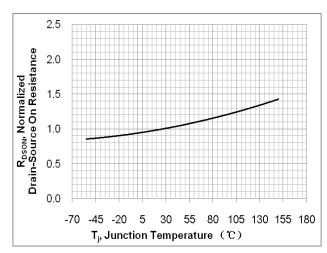


Fig. 7. Gate charge characteristics

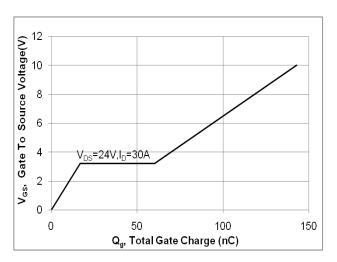


Fig. 9. Maximum safe operating area

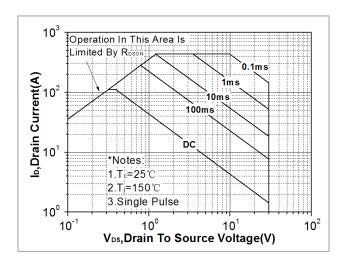


Fig. 11. Transient thermal response curve

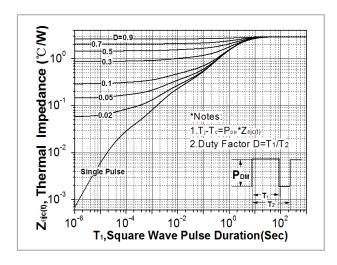


Fig. 8. Capacitance Characteristics

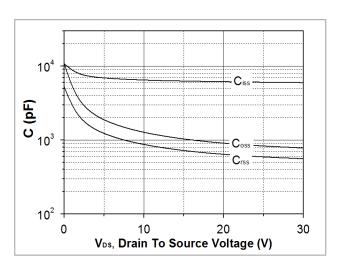
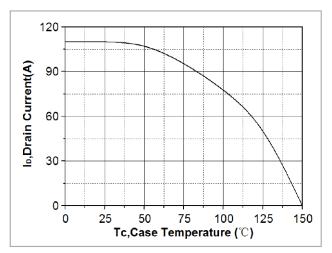


Fig. 10. Maximum drain current vs. case temperature



# **Test Circuit**

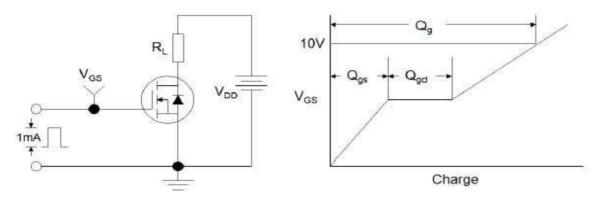


Figure1:Gate Charge Test Circuit & Waveform

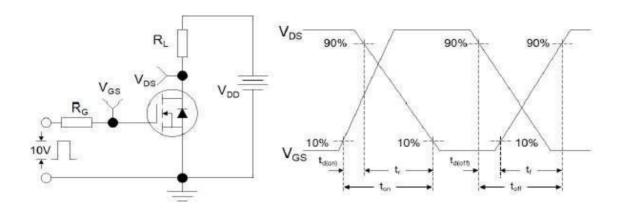


Figure 2: Resistive Switching Test Circuit & Waveforms

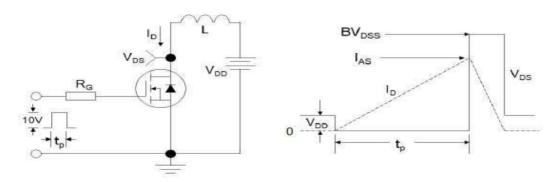
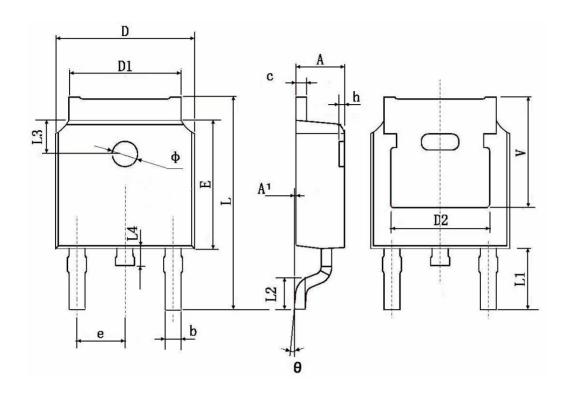


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

# **TO-252-2L Package Information**



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
А	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350 TYP. 0.211 TYP.		1 TYP.		



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